	Application No.	Applicant(s)	
Notice of Allowability	10/607,410	LI ET AL.	
	Examiner	Art Unit	
	Richard A Rosenberger	2877	
The MAILING DATE of this communication appeared all claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this app or other appropriate communication IGHTS. This application is subject to	olication. If not include will be mailed in due	ed course. <b>THIS</b>
1. This communication is responsive to			
2. The allowed claim(s) is/are <u>1-34</u> .			
3. The drawings filed on <u>25 June 2003</u> are accepted by the Examiner.			
<ul> <li>4. ☐ Acknowledgment is made of a claim for foreign priority unallocation.</li> <li>a) ☐ All b) ☐ Some* c) ☐ None of the:  1. ☐ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)).  * Certified copies not received:</li> <li>Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.</li> <li>5. ☐ A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give</li> </ul>	e been received. e been received in Application No cuments have been received in this of this communication to file a reply MENT of this application.	national stage applica complying with the red	quirements
6. CORRECTED DRAWINGS (as "replacement sheets") mus	st be submitted.		
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached			
1)  hereto or 2)  to Paper No./Mail Date			
(b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date			
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t			e back) of
7. DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT			Note the
<ul> <li>Attachment(s)</li> <li>1. ☑ Notice of References Cited (PTO-892)</li> <li>2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date 9/29/2003</li> <li>4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material</li> </ul>	5. Notice of Informal P 6. Interview Summary Paper No./Mail Dat 7. Examiner's Amendr 8. Examiner's Stateme 9. Other	(PTO-413), te ment/Comment	

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1. The following is an examiner's statement of reasons for allowance:

2. The art does not teach or suggest the combination claimed. In particular, the art does not teach or suggest determining parameters of features on a transparent of semi-transparent substrate, comprising measuring a response spectrum of light from the substrate, computing a complex-values response due to the features and the substrate, and determining the parameter by using both the response spectrum and the complex valued response.

Johnson (US 5,452,091) discusses measuring a physical parameter (thickness) of a feature (a thin film) on a substrate. The reference teaches obtaining from a calibration wafer a complex-valued response (column 4, line 40). The complex-valued response for the calibration wafer is used, in combination with "standard curve fitting methods" using a response spectrum from the sample to determine the parameter of the feature. The reference does not determine the complex-valued response due to the features and the substrate of the sample, as claimed herein.

Sano et al (US 4,850,711) discusses the complex amplitude-transmission and /or complex amplitude-reflection coefficients (column 4, lines 49, 54), but does not appear to measure and use a response spectrum; the reference does disclose using two different wavelengths (the embodiment of figures 8 and 9), but two discrete wavelengths in not a spectrum.

Borden (US 6,426,644) determines properties of a sample, such as junction depth and the number of active dopants as a function of depth, using a measurement of complex

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reflectance (column 13, lines 18-29). The reference does not appear to use this complex reflectance in combination with a spectrum in the manner of the claims.

Folkard et al (US 5,061,072) discusses determining the complex reflection of a sample. The reference e does not teach using a spectrum as part of the analysis.

- 3. Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."
- 4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Richard A Rosenberger whose telephone number is (571) 272-2428. The examiner can normally be reached on Monday through Friday during the hours of 8:00-4:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley, Jr. can be reached on (571) 272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

R. A. Rosenberger22 September 2004

Richard A. Rosenberger Primary Examiner

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